

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10750175	DANG ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Trimmings, John P	2117

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
326/41,38, 714/724,726,734,731,30. Text strategy attaced (see EAST printout).	4/9/2007	jpt
Dble Patent Search: Negative (see printout).	4/9/2007	jpt
NPL Search: scan chains and fpga or pld and test mode.	4/9/2007	jpt
326/41,38,40, 714/724,727,725,729,742,726,734,731,30. Text strategy attached (see EAST printout).	1/14/2008	jpt
Dble Patent Search: Negative (see printout).	1/17/2008	jpt
NPL Search: Negative.	1/17/2008	jpt

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>